

## 1997 Technical Paper Reviewers

Magdy Abadir  
Motorola

Jacob A. Abraham  
University of Texas

Miron Abramovici  
Lucent Technologies - Bell Labs

John Acken  
Intel

R. Dean Adams  
Dartmouth College

Saman Adham  
Northern Telecom

Vishwani D. Agrawal  
Lucent Technologies - Bell Labs

Robert C. Aitken  
Hewlett-Packard

Mark Alison  
Integrated Measurement Systems

Anthony P. Ambler  
University of Texas

Billy Antheunisse  
Texas Instruments

Richard Antley

James R. Armstrong  
Virginia Polytechnic Inst. & State  
University

Ralf Arnold  
Siemens AG

John Aslanian  
Motorola

LaNae Avra  
Stanford University

Keith Baker  
Philips ED&T/Test

Hari Balachandran  
Texas Instruments

Arun Balakrishnan  
LSI Logic

Savita Banerjee  
AT&T Bell Labs

Stefano Barbagallo  
ITALTEL

Mark R. Barber  
Lucent Technologies

Jim Barby  
University of Waterloo

Luis Basto  
Advanced Micro Devices

James Beausang  
Synopsys

John Bednar  
Lucent Technologies

Ben Bennetts  
LogicVision

Michael Bershteyn  
Quickturn Design Systems

Sandeep Bhatia  
Duet Technologies

Dilip Bhavsar  
Digital Equipment

Andy Bishop  
Quantum

Shawn Blanton  
Carnegie-Mellon University

Harold Blount  
MITEL, Ltd.

Eberhard Boehl  
Robert Bosch GmbH

George Booth  
Hewlett-Packard

Soumitra Bose  
NEC USA

Rick Boyle  
Tandem Computers

Daniel Brand  
IBM

Robert Brayton  
University of California

Melvin Breuer  
University of S. California

Ben Brown  
Teradyne

Bill Bruce  
Motorola

Eric M.J. Bruls  
Philips Research Labs

Scott Bullock  
Teradyne

Bill Burdick  
GE CRD

Dwayne Burek  
LogicVision

Mark Burns  
Texas Instruments

Michael L. Bushnell  
Rutgers University

Kenneth Butler  
Texas Instruments

Teodor Calin  
TIMA

Joan Carletta  
Case Western Reserve University

Gunnar Carlsson  
Ericsson Components

Gary E. Carver  
Lucent Technologies

Ron Caton  
Mitel

Trent Cave  
Integrated Measurement Systems

Eduard Cerny  
University of Montreal

Michael Chaggaris  
IMS

Krishnendu Chakrabarty  
Boston University

Tapan J. Chakraborty  
Lucent Technologies - Bell Labs

Srimat T. Chakradhar  
NEC, USA

Sreejit Chakravarty  
State University of NY

Ronnie Chan  
Kinetix Microsystems

Ramamurti Chandramouli  
LogicVision

Dan Chaney  
Boeing Defense & Space Group

Paul Chang  
IBM

Abhijit Chatterjee  
Georgia Institute of Technology

P. Pal Chaudhuri  
Intel

Wu-Tung Chen  
Mentor Graphics Company

Xinghao Chen  
IBM Microelectronics

Kwang-Ting Tim Cheng  
University of California

Brian Chess  
Hewlett-Packard

Vivek Chickermane  
IBM

Dick Chiles  
NCR

Reed Christensen  
Intel

Bruce Cockburn  
University of Alberta

Stephen Cohen  
Analog Devices

Dennis Conti  
IBM

Fulvio Corno  
Politecnico di Torino

Bernard Courtois  
TIMA

Ed Crane  
AT&T

Phillip Crawley  
Crystal Semiconductor

Al Crouch  
Motorola

John Crownover  
Motorola

Marcello Dalpasso  
University of Ferrara

Ramaswami Dandapani  
University of Colorado

Martin Daniels  
Texas Instruments

Gobinda Das  
IBM

Daniel Daskiewich  
Rome Laboratories

# International Test Conference *1997 Technical Paper Reviewers*

Rene David  
Laboratoire d'Automatique de  
Grenoble

Scott Davidson  
Sun Microsystems

Brendan Davis  
BD Consulting

Frans de Jong  
Philips Research Labs.

Kaushik De  
LogicVision

Ian D. Dear  
Brunel University

Warren H. Debany  
Rome Laboratory / ERDA

Michael Dewitt  
Lucent Technologies

Sujit Dey  
NEC USA

Chennian Di  
IBM

Alan DiCato

Chryssa Dislis  
Reading University

Noel Donlin  
US Army MICOM

Arthur E. Downey  
Credence Systems

Benoit Dufort  
McGill University

David K. Durham  
Electroglas

Peter Dziel  
Stratus Computer

Martin H. Eastburn  
Schlumberger ATE

Thomas Eberle  
Mentor Graphics

## 1997 Technical Paper Reviewers

Aiman H. El-Maleh  
Mentor Graphics

Jacob El-Ziq  
Synopsys

Mark A. Erle  
IBM

Daniel Fan  
Schlumberger

Des Farren  
Motorola

Michele Favalli  
DEIS - University of Bologna

F. Joel Ferguson  
Univ California

Joan Figueras  
Univeristat Politecnica de Catalunya

Andrew Flint  
AT&T Wireless Services

Jamie Fontenot  
Motorola

Donato Forlenza  
IBM

Piero Franco  
Synopsys

Michael T. Freeman  
Scientific-Atlanta

Doug Frey  
Lehigh University

Jack Frost  
Integrated Measurement Systems

W. Kent Fuchs  
Purdue University

Kazuyasu Fujishima  
Mitsubishi Electric

Masahiro Fujita  
Fujitsu Labs of America

Hideo Fujiwara  
Nara Institute of Science &  
Technology

Mike Gaffney  
Intel

Nikos Gaitanis  
NCSR Demokritos

Jim Gasbarro  
Rambus

Anne Gattiker  
Carnegie Mellon University

Richard Gaunt  
Integrated Measurement Systems

Marwan Gharaybeh  
Synopsys

Grady Giles  
Motorola

Uwe Glaeser  
GMD-SET

Clay Gloster  
North Carolina State University

Michael Goessel  
University of Potsdam

Melvyn Goveas  
Intel

Xinli Gu  
Synopsys

Aarti Gupta  
NEC USA

Rajesh Gupta  
University of California

Sandeep Gupta  
University of S. California

Sanjay Gupta  
Nortel Semiconductors

Mark C. Hansen  
Delco Electronics

Ramesh Harjani  
University of Minnesota

Ismed Hartanto  
Hewlett Packard

Abu Hassan  
Mentor Graphics

Xavier Haurie  
Analog Devices

Charles F. Hawkins  
University of New Mexico

Evan Hawrysh  
Cadence Design Systems

John P. Hayes  
University of Michigan

Martin Heimann  
Lucent Technologies

Sybille Hellebrand  
University of Siegen

Hank Henderson  
Testware

Keerthi Heragu  
University of Illinois

Yoshinobu Higami  
Osaka University

Jim Homer  
Lucent Technologies

Michael Hsiao  
University of Illinois

Frank F. Hsu  
University of Illinois

Greg Huber  
Intel

Jose Huertas  
University of Seville

Joseph Hughes  
Georgia Institute of Technology

Leendert Huisman  
IBM Microelectronics

Craig Hunter  
Motorola

Robert E. Huston  
Credence Systems

Jim Icuss  
CommQuest Technologies

Tomoo Inoue  
Nara Institute of Science &  
Technology

Mahesh A. Iyer  
Synopsys

Dhanendra Jani  
Intel

Peter Janssen  
Philips Research

Najmi Jarwala  
AT&T Wireless Services

Niraj Jha  
Princeton University

Daniel D. Johnson  
Lucent Technologies

Kirsten Johnson  
Integrated Measurement Systems

Clark Jones  
Schlumberger

Don Josephson  
Hewlett-Packard

Seiji Kajihara  
Kyushu Institute of Technology

Bozena Kaminska  
Opmaxx

Arvind K. Karandikar  
Intel

Ali Kavari  
Kimchuk, Inc.

Wu-diann Ke  
Cadence Design Systems

David C. Keezer  
Georgia Institute of Technology

Neil Kelly  
LTX

Hans Kerkoff  
Mesa Research Institute

Javad Khakbaz  
Tandem Computers

John M. Khoury  
Columbia University

Nash Khouzam  
National Semiconductor

Bruce Kim  
Tufts University

Kee Sup Kim  
Intel

Charles R. Kime  
University of Wisconsin

Kozo Kinoshita  
Osaka University

Anjali Kinra  
Texas Instruments

# International Test Conference *1997 Technical Paper Reviewers*

Robert H. Klenke  
University of Virginia

Bernd Koenemann  
LogicVision

Mario Konijnenburg  
Delft University

Kevin Kornegay  
Purdue University

Randy Kramer  
Teradyne

Andreas Kuehlmann  
IBM

Sandeep Kumar  
Lucent Technologies

Mary Kusko  
IBM

Barry LaBonte  
Teradyne

Kenneth Laker  
University of Pennsylvania

Kabada Lakshikumar  
Lucent Technologies

Christian Landrault  
LIRMM

Tom Langford  
Symbios Logic

Kenneth Lanier  
LTX

Tracy Larrabee  
University of California

Jim Larson

David Lavo  
University of California

Wai-On Law  
Motorola

Joseph Lazar  
Canadian Marconi Company

## 1997 Technical Paper Reviewers

Duy K. Le  
Lucent Technologies

Jaushin Lee  
Silicon Graphics

Mike Lee  
Avanti

Donald H. Lenhart  
Kansas State University

Lenny Leon  
LTX

Regis Leveugle  
Institut National Polytechnique de  
Grenoble

Jien-Chung Lo  
University of Rhode Island

Fabrizio Lombardi  
Texas A&M University

David E. Long  
AT&T Bell Laboratories

Loai Louis  
McGill University

Murice Lousberg  
Philips ED&T/Test

Albert Lu  
Analog Devices

Marcelo Lubaszewski  
DELET/URFGS

Timothy D. Lyons  
Teradyne

Tony Ma  
Synopsys

Samy Makar  
Cirrus Logic

Mori Malowany  
MITEL, Ltd.

Tony Mandia  
Teradyne

Kenneth Mandl  
Teradyne

James Marek  
GenRad

Peter Marwedel  
Universitat Dortmund

Jean-Pierre Masbou  
Intel

Alida Mascitelli  
Synopsys

Gregory Mastin  
Motorola

Ben Mathew  
Silicon Graphics

Jose S. Matos  
DEEC - FEUP

Colin Maunder  
BT Laboratories

Peter C. Maxwell  
Hewlett-Packard

Kevin McCauley  
IBM

Edward J. McCluskey  
Stanford University

John E. McDermid  
Hewlett-Packard

Patrick McHugh  
LogicVision

Prem R. Menon  
University of Massachusetts

Sankaran M. Menon  
South Dakota School of Mines &  
Technology

Cecilia Metra  
Bologna University

Dean Micoley  
Alliant Techsystems

Scott F. Midkiff  
Virginia Polytechnic Inst. & State  
University

Joseph A. Mielke  
Integrated Measurement Systems

Al Miller  
Digital Equipment

Will Miller  
Integrated Measurement Systems

Linda Milor  
Advanced Micro Devices

Jose Miranda  
Lucent Technologies

Miguel A. Miranda  
IMEC Lab

Jim Monzel  
IBM

John Moore  
Teradyne

Amir Mottaaz  
Synopsys

Debaditya Mukherjee  
Intel

Tom Munns  
Motorola

Fidel Muradali  
Hewlett Packard

Brian T. Murray  
General Motors

Marc Mydill  
Texas Instruments

Suresh Nadig  
Digital Equipment

Naveena Nagi  
LogicVision

Daniel Neebel  
James Madison University

Wayne Needham  
Intel

Jeffrey Newquist  
Univ of Illinois

Michael Nicolaidis  
TIMA/INPG

Phil Nigh  
IBM Microelectronics

Dimitris Nikolos  
University of Patras

Charles A. Njinda  
Advanced Micro Devices

Jim O'Reilly  
Hewlett-Packard

Steven F. Oakland  
IBM

Michael Ohletz  
Universitaet Hannover

Ted Olivarez  
Integrated Measurement Systems

Max Olsen

Toshinobu Ono  
NEC Corp.

Steven Oostdijk  
Phillips ED&T/Test

Alex Orailoglu  
University of California

William R. Ortner  
Lucent Technologies

Christos A. Papachristou  
Case Western Reserve University

Prashant S. Parikh  
Lucent Technologies

Bong-Hee Park  
Intel

Kenneth Parker  
Hewlett-Packard

Michael Parot  
Thomson-CSF

Praveen Parvathala  
Intel

Antonis Paschalis  
NCSR Demokritos

Janak H. Patel  
University of Illinois

Stephen Pateras  
LogicVision

Rajesh Pathak  
AMD

Srinivas Patil  
Mentor Graphics

John Peters  
Fujitsu Microelectronics

Stanislav Piestrak  
Wroslav University

Slawomir Pilarski  
Synopsys

Andy Pindar  
Schlumberger Tech.

Carl Pixley  
Motorola

James F. Plusquellic  
University of Pittsburgh

# International Test Conference 1997 Technical Paper Reviewers

Irith Pomeranz  
University of Iowa

Kenneth E. Posse  
Hewlett-Packard

Miodrag Potkonjak  
University of California

Theo J. Powell  
Texas Instruments

Paolo Prinetto  
Politecnico di Torino

Cheryl Prunty  
Intel

Carol Pyron  
Motorola

Anand Raghunathan  
NEC USA

Suresh Rai  
Louisiana State University

Krishna B. Rajan  
Sun Microsystems

Janusz Rajski  
Mentor Graphics

Rochit Rajsuman  
Equator Technologies

Hira Ranga  
Credence Systems

Douglas W. Raymond  
Teradyne

Jeff Rearick  
Hewlett-Packard

Lakshmi Reddy  
IBM

Sudhakar M. Reddy  
University of Iowa

Mike Reed  
Motorola

Michel Renovell  
LIRMM

## 1997 Technical Paper Reviewers

Bruno Ricco  
University of Bologna

David Rich  
Lucent Technologies

Andrew Richardson  
Lancaster University

Gary Richey  
Texas Instruments

Scott Richter  
IBM

Alan Righter  
Sandia National Laboratories

Gordon W. Roberts  
McGill University

Gordon D. Robinson  
Credence Systems

John Robinson  
University of Iowa

Todd Rockoff  
Advantest America R&D Center

Jeffrey Roehr  
Analog Devices Inc

Carlos Roman  
Lucent Technologies - Bell Labs

Eric Rosenfeld  
LTX

Daniel Rosenthal  
Schlumberger ATE

Lynn Roszel  
Texas Instruments

Rabindra K. (Rob) Roy  
Intel

Elizabeth Rudnick  
University of Illinois

Bob Russell  
Bull HN Information

Steven A. Rutledge  
Boeing Defense and Space Group

Paul Ryan  
Intel

Daniel G. Saab  
Case Western Reserve University

Manoj Sachdev  
Philips Research Labs

Kewal Saluja  
University of Wisconsin

Edgar Sanchez-Sinencio  
Texas A&M University

Yvon Savaria  
Ecole Polytechnique

Jayashree Saxena  
Texas Instruments

Ulrich Schoettmer  
Hewlett-Packard

Philip Seitzer  
Lucent Technologies

John Shen  
Carnegie Mellon University

John W. Sheppard  
ARINC Research

Masao Shimizu  
Advantest America R&D Center

William Randy Simpson  
Institute for Defense Analyses

Adit Singh  
Auburn University

Ken Skala  
Kinetix Test Systems

Phil Smith  
Teradyne

Dima Smolyansky  
Integrated Measurement Systems

Lori Smudde  
IBM

Thomas Snethen  
IBM

Jerry M. Soden  
Sandia National Laboratories

Egor Sogomonyan  
Russian Academy of Science

Max Solomon  
LTX

Mani Soma  
University of Washington

Matteo Sonza Reorda  
Politecnico di Torino

John Spignese  
Integrated Measurement Systems

Donald Staab  
Tandem Computers

Dale Steen

Michael L. Steinberger  
Lucent Tech - Bell Labs

Olaf Stern  
ABB Corporate Research, Ltd.

Susana Stoica  
Ford Motor Company

Robert L. Stokes  
Sensors & Communication Systems

Charles Stroud  
University of Kentucky

Chauchin Su  
National Central University

X. Sun  
University of Alberta

Stephen Sunter  
LogicVision

Tony Suto  
GenRad

Earl E. Swartzlander, Jr.  
University of Texas

Masahide Takada  
NEC

Masaaki Tanno  
NTT LSI Labs

Anthony Taylor  
Credence

Joao Paulo Teixeira  
INESC/IST

Al Tejada  
Teradyne

Robert S. Tepper  
Applied Micro Circuits

Claude Thibeault  
Ecole de Technologie Superieure

Jack Thomas  
Integrated System

Michael Toner  
Nortel Semiconductors

Carol Tong  
Sunrise Test Systems

Nur A. Touba  
University of Texas

Chris Toumazou  
Imperial College

Paul Tracy  
Lucent Technologies

Steve Trimberger  
Xilinx

Pieter Trouborst  
Northern Telecom

Jon Turino  
Integrated Measurement Systems

Jerzy Tyszer  
Poznan University of Technology

Bill Underwood  
Sunrise Test Systems

Dave Vallett  
IBM Microelectronics

Ad J. van de Goor  
Delft University

Hans van der Linden  
Delft University

James Van Derwiele  
Lucent Technologies

Dieu Van Dinh  
Motorola

Benoit Veillette  
McGill University

Math Verstraelen  
Phillips Research

Heinrich Theo. Vierhaus  
Technical University of Brandenburg

Russell J. Wagner  
Rockwell International

Michael G. Wahl  
Universitaet Siegen

Robert Walden  
Lucent Technologies

Kenneth M. Wallquist  
Philips Semiconductors

Li Chung Wang  
Motorola

Bruce Webster  
Teradyne

# International Test Conference *1997 Technical Paper Reviewers*

Robert J. Wenzel  
Georgia Institute of Technology

Chin-Long Wey  
Michigan State University

Donald L. Wheeler  
IBM

Peter Wohl  
Advanced Test Technologies

Justin Woyke  
IBM

Joseph Wrinn  
Teradyne

David Wu  
Intel

Shianling Wu  
Lucent Technologies

Hans-Joachim Wunderlich  
University of Stuttgart

Greg Young  
Texas Instruments

Charles Yount  
Intel

Joel Yuen  
Intel

Tom Ziaja  
IBM

Yervant Zorian  
LogicVision